



# *A novel 3D embedded gate FET Device concepts and modeling*

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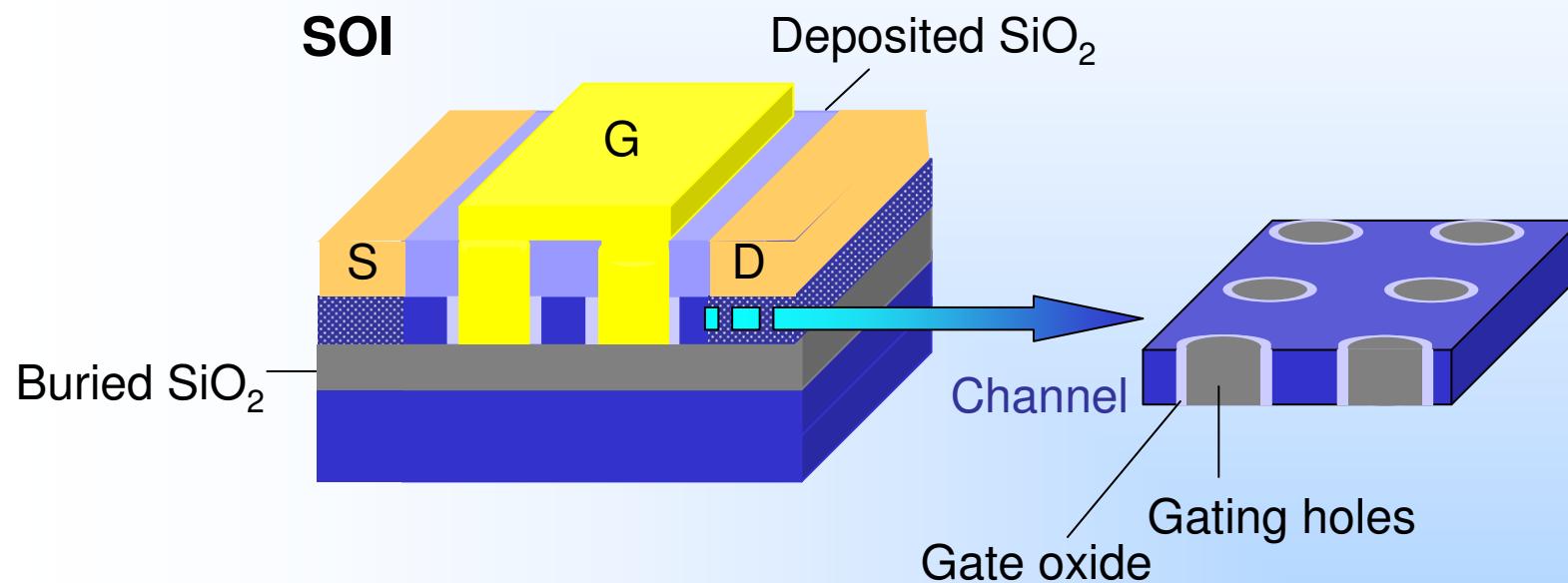
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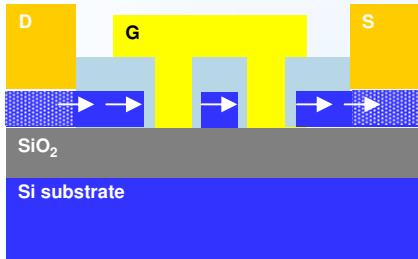
- Device geometry
  - Planar multi-gate structure
- Operation
  - DIBL control
- DC characteristics
  - $g_m/I_{DS}$ ,  $g_d$ , S, DIBL
- AC characteristics
  - Planar structure
- Conclusions

# Device geometry

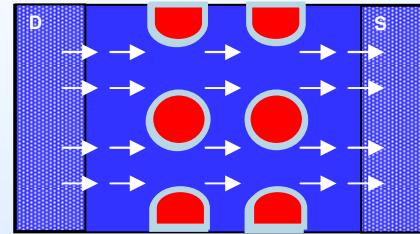


**Planar structure  
Multi gate control  
Two rows of gate holes**

# Screen-Grid FET (SGFET)



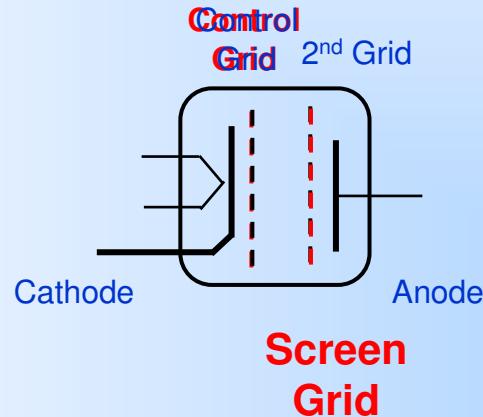
Side view cross section



Top view cross section

- Buried oxide
- Thermal oxide
- Silicon channel
- Contact
- Silicon substrate
- Current flow

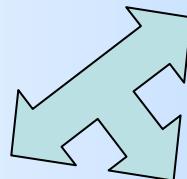
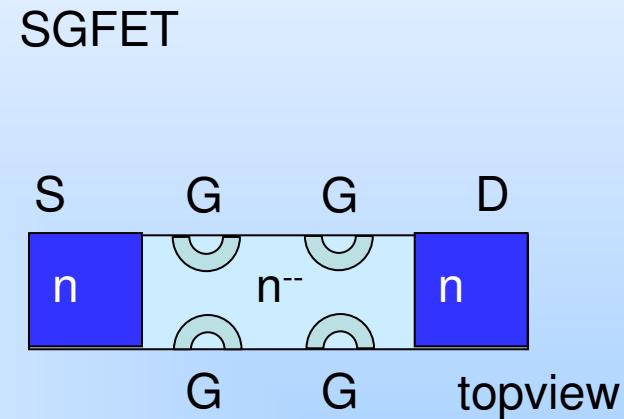
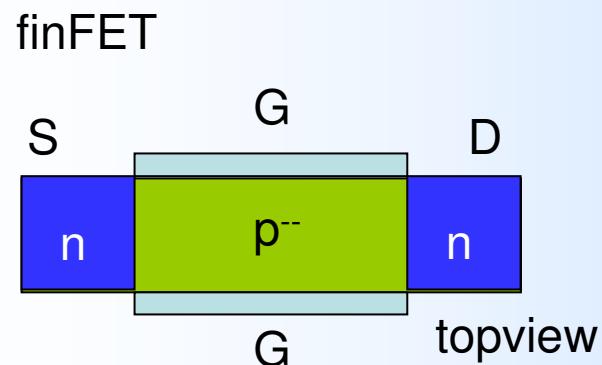
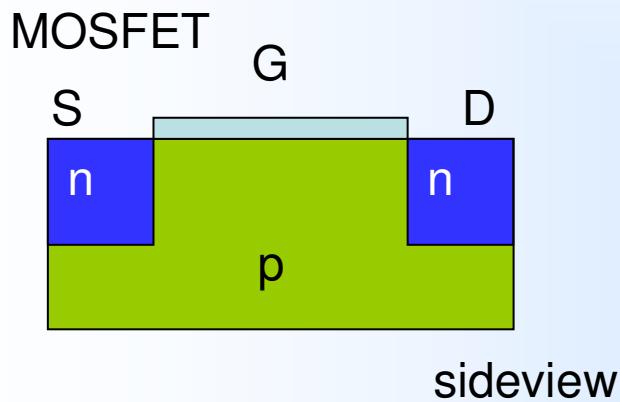
Tetrode



SG – ‘Screen Grid’ principle from vacuum tube technology

# What sets the SGFET apart from other FETs?

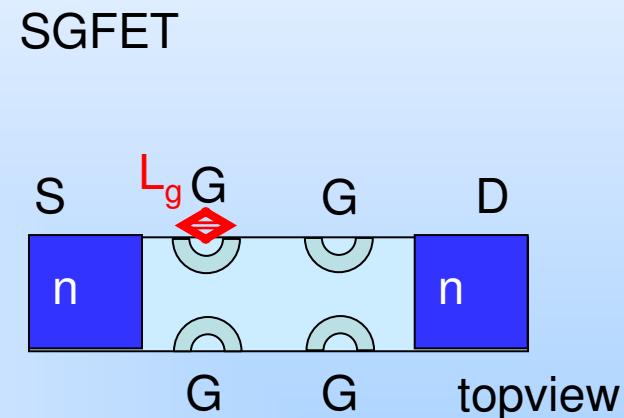
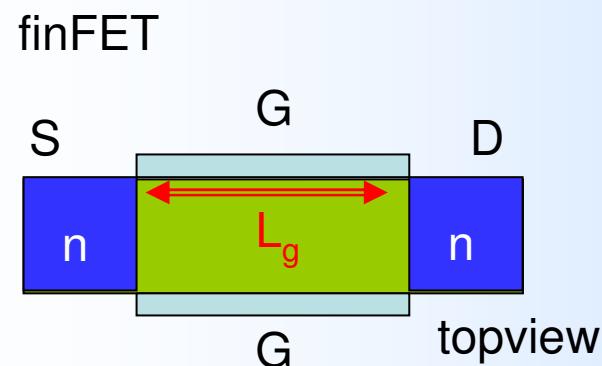
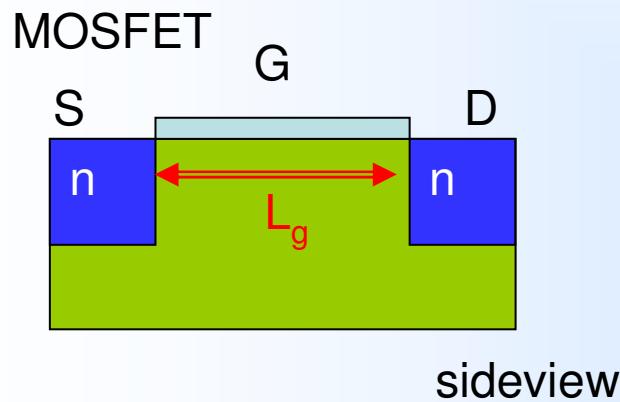
- 1) Doping type of channel compared to ohmic contacts



Work best with ***un-doped*** channel

# What sets the SGFET apart from other FETs?

2) source-drain distance and channel length uncoupled



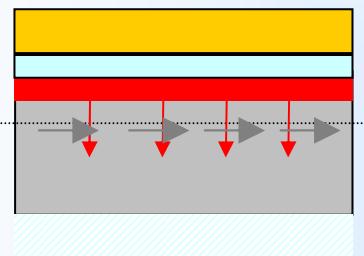
Gate length and source-drain distance  
un-coupled

A large green arrow points downwards from the finFET diagram to the SGFET diagram, indicating a comparison or transformation between the two structures.

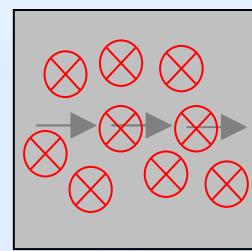
# Operation of the SGFET.

## Gating Effect:

- Conventional MOSFET gating

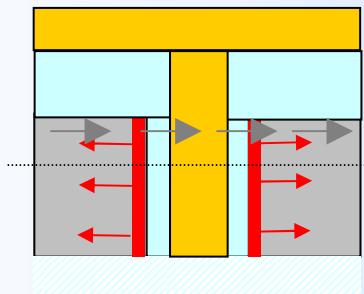


Side View

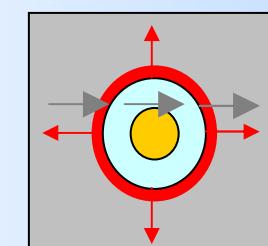


Top View

- Gate Electrode
- Gate/Field Oxide
- Si Channel
- Depletion region
- Buried oxide
- Current flow
- Gating action
- ⊗ Gating action



Side View

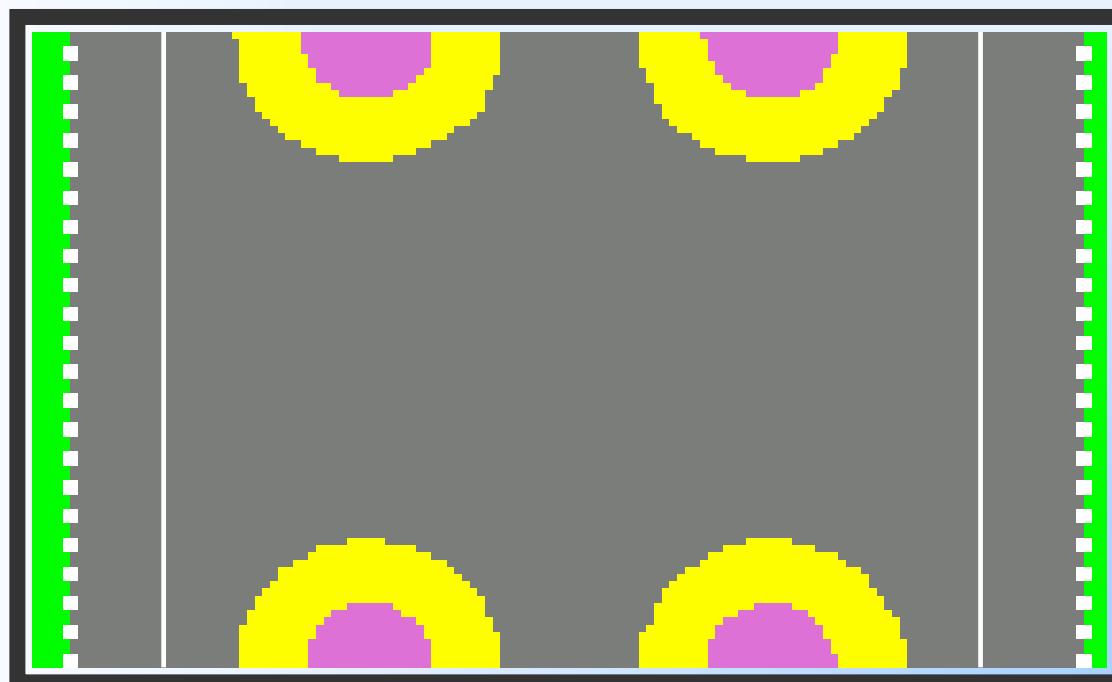


Top View

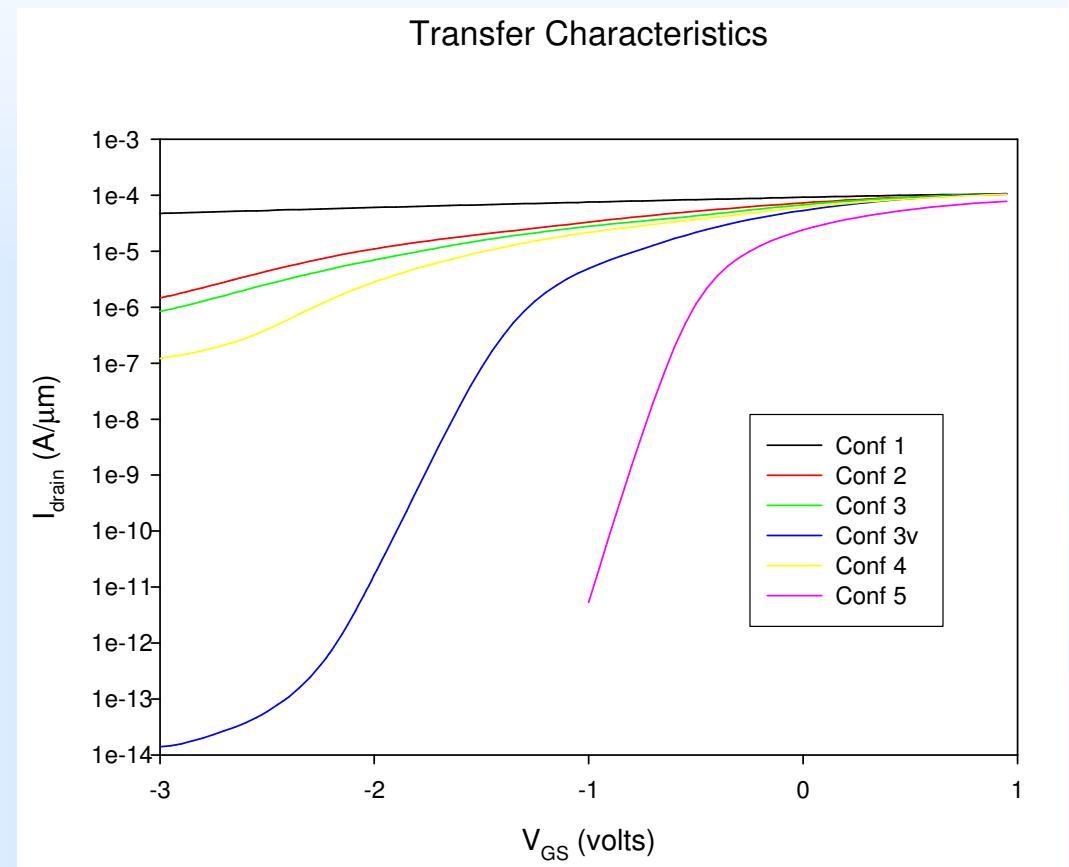
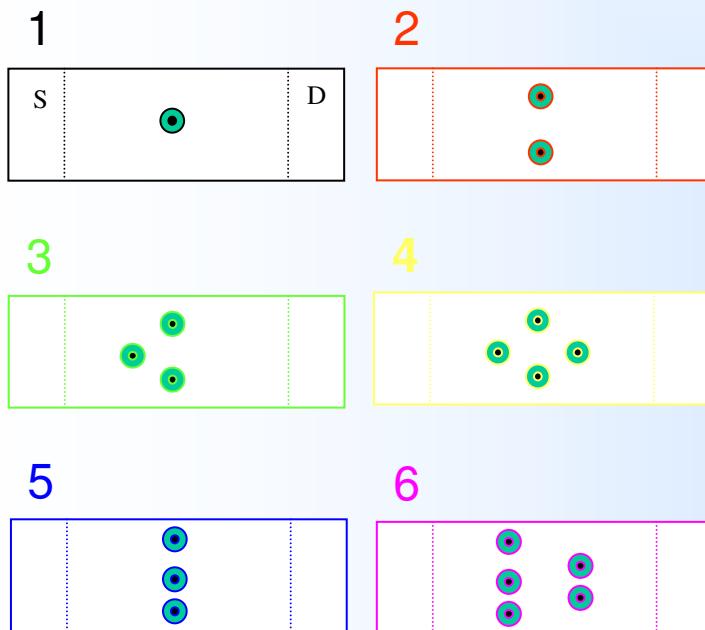
- SGFET gating

# Operation of the SGFET.

Simulated depletion region  $V_D=0.05V$ ,  $V_G=0V$  to -1V

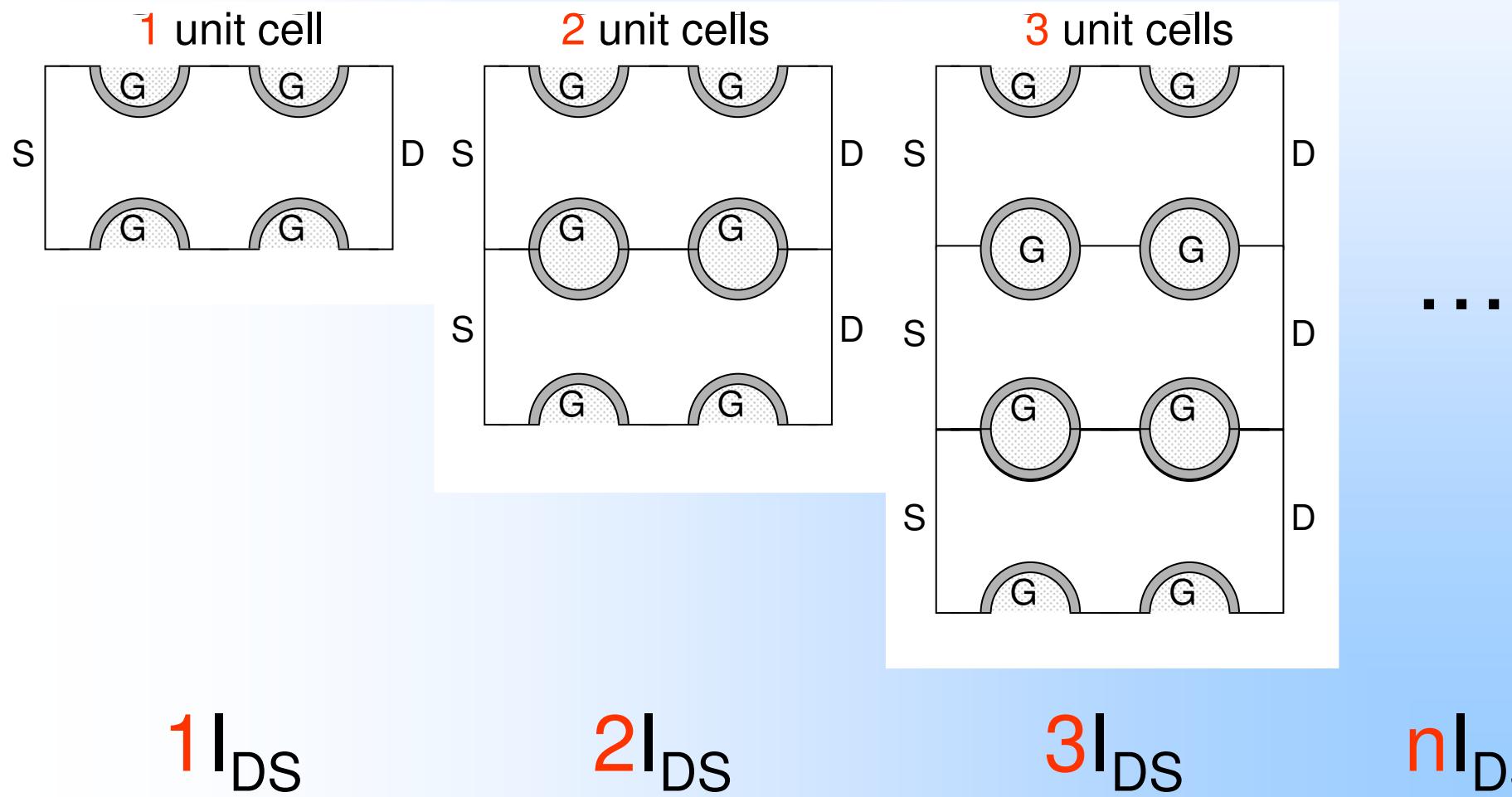


# DC characteristics alternative gate configurations

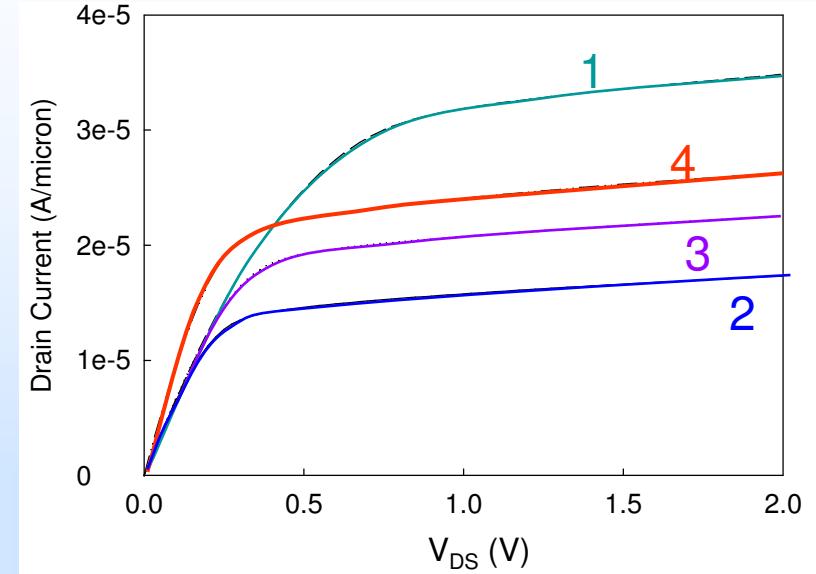
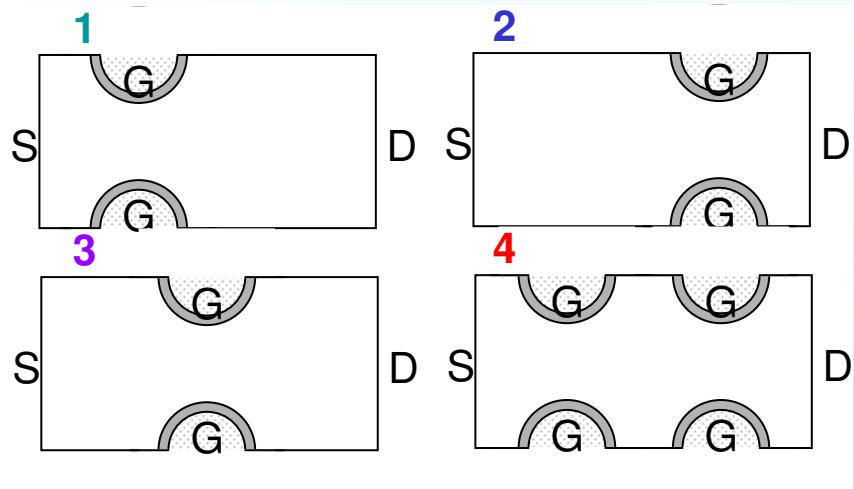


# Optimal gate configuration

Principle of unit cell

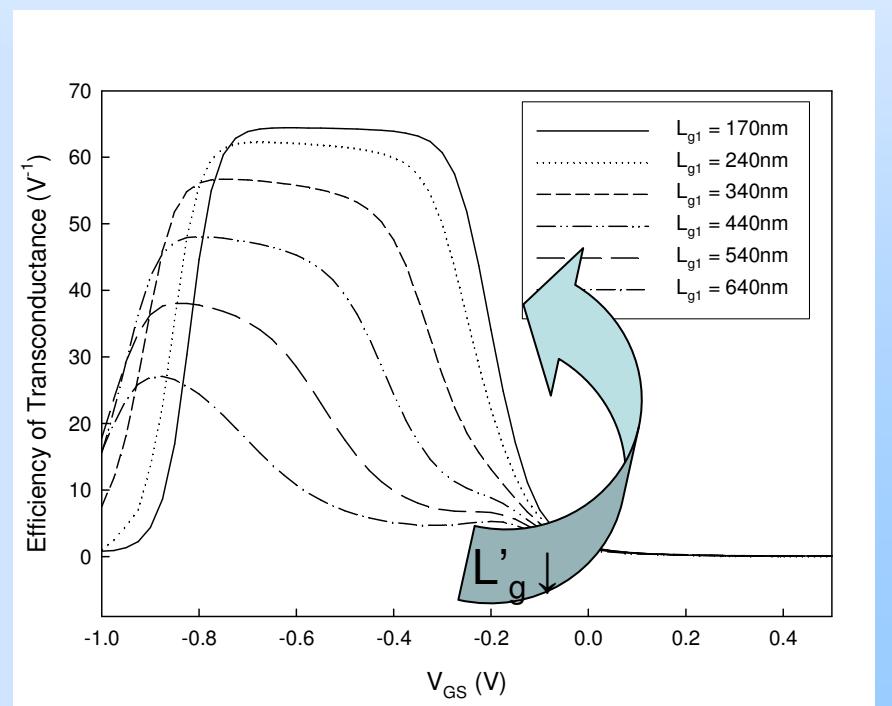
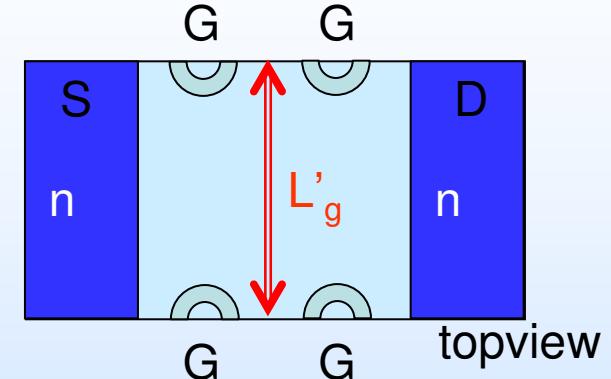
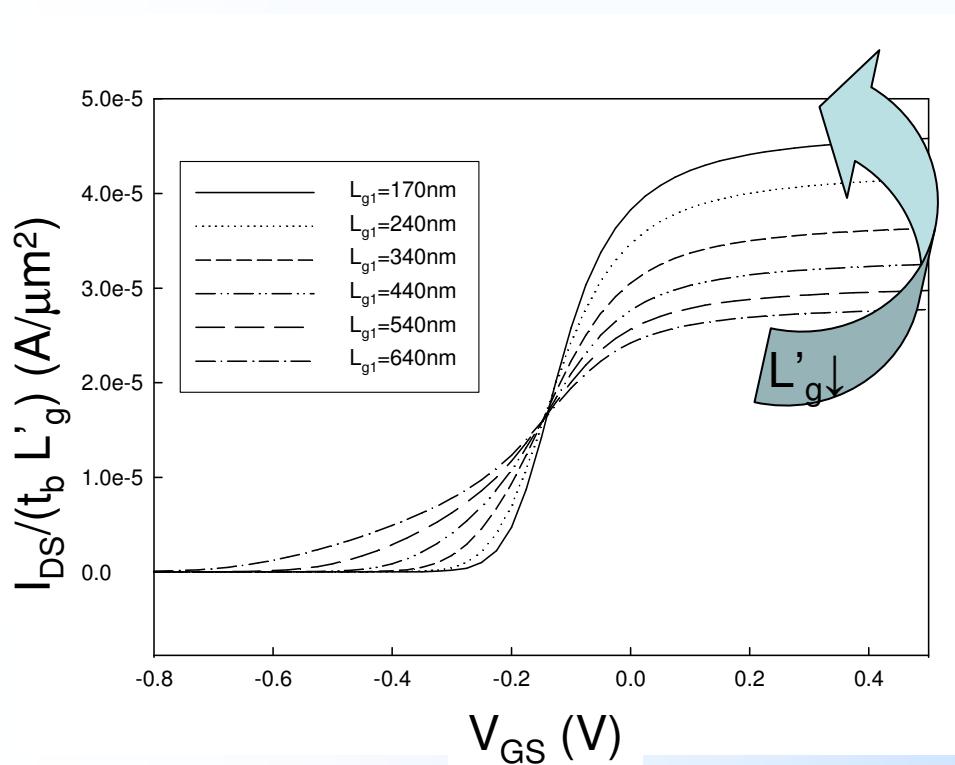


# Influence of gate position

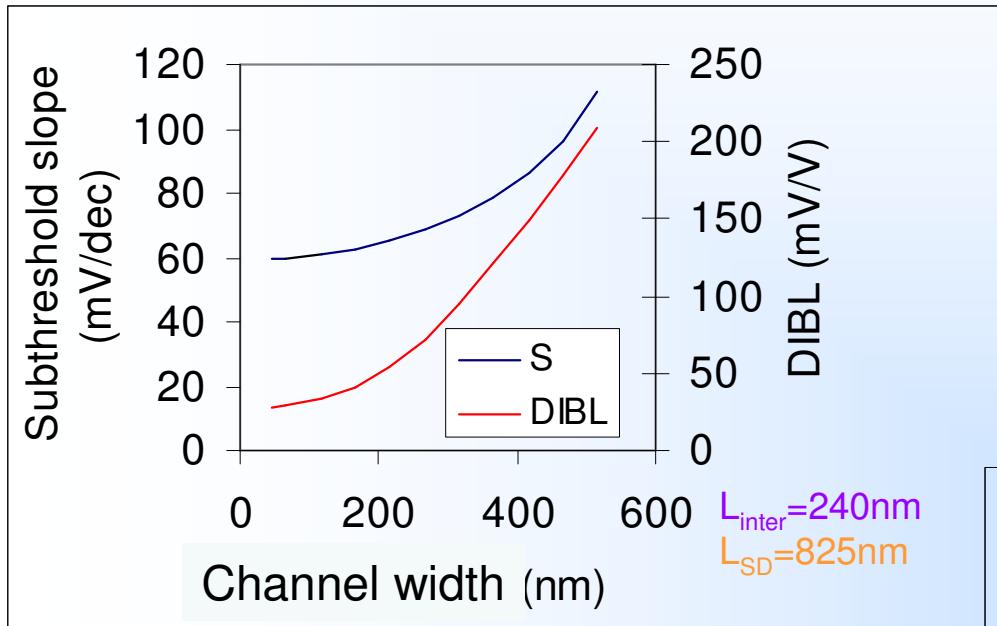


| Configuration no   | 1                 | 2                | 3            | 4       |
|--|-------------------|------------------|--------------|---------|
| position of rows   | 1 row near source | 1 row near drain | 1 row middle | 2 rows  |
| DIBL (mV/V)  | 59.8              | 100.8            | 79.5         | 42.4    |
| S (mV/dec) @ $V_{DS}=0.1V$                                       | 71.3              | 70.7             | 70.0         | 63.0    |
| $g_{m\max}$ (S/ $\mu\text{m}^2$ ) @ $V_{DS}=0.1V$                | 1.17e-4           | 9.49e-5          | 1.07e-4      | 1.55e-4 |
| $g_{d\min}$ ( $\mu\text{S}/\mu\text{m}^2$ ) @ $V_{GS}-V_{th}=0V$ | 0.846             | 0.397            | 0.487        | 0.152   |

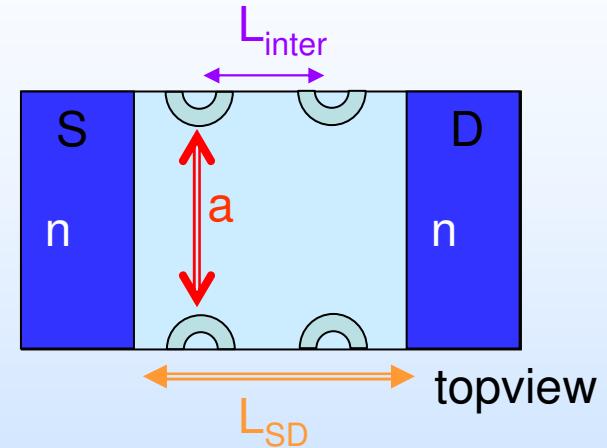
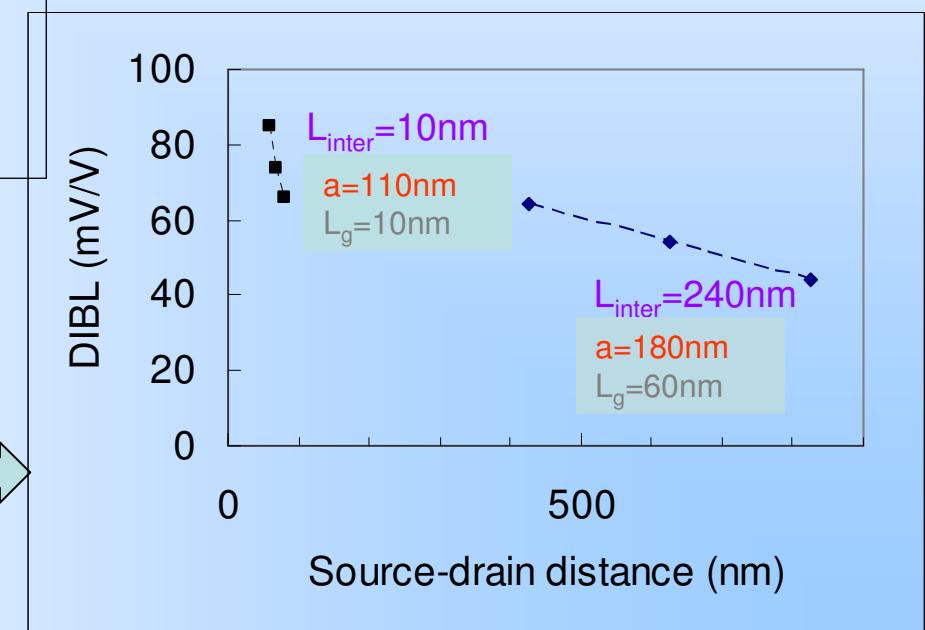
# DC characteristics



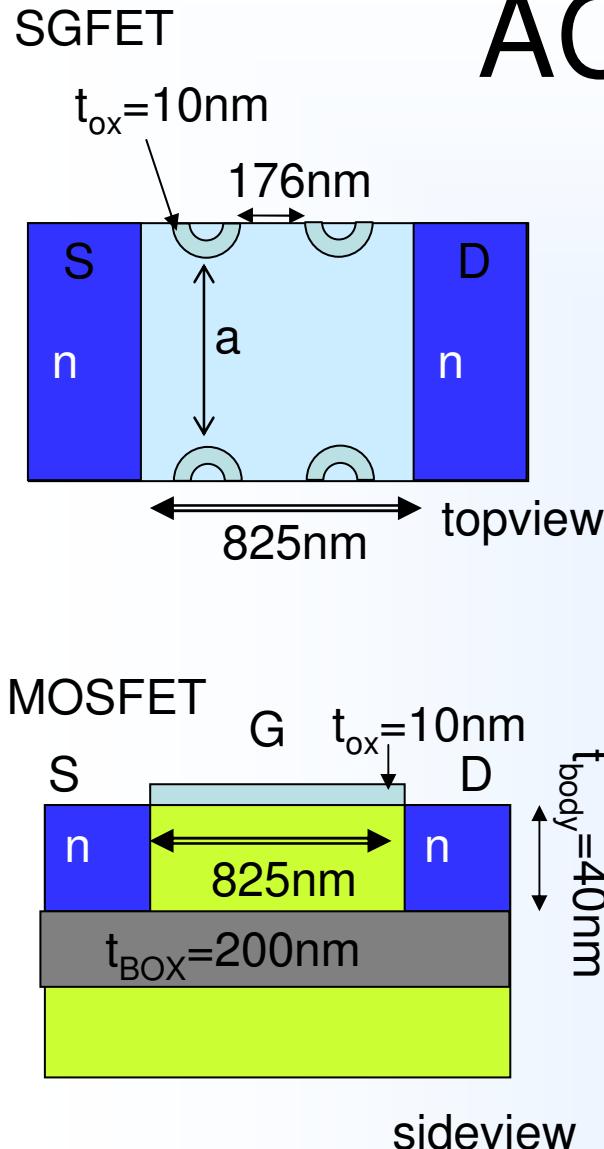
# DC characteristics



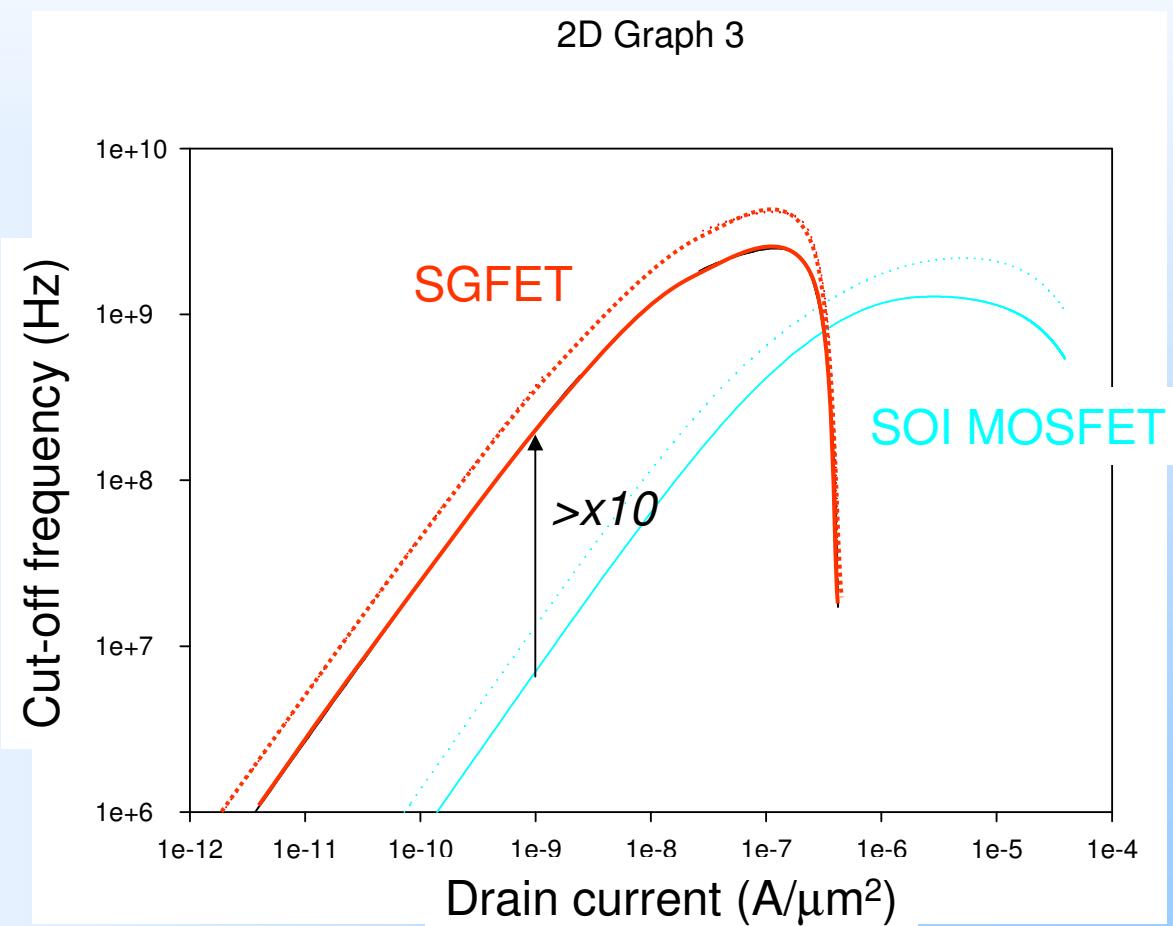
DIBL & S $\downarrow$  for a $\downarrow$   
DIBL $\uparrow$  for  $L_{\text{SD}}\downarrow$  but controlled by  $L_{\text{inter}}$



# AC characteristics



$$N_{\text{channel}} = 10^{15} \text{ cm}^{-3}$$



# Conclusions

- Novel planar multi gated FET is proposed with a gating configuration similar to the tetrode → **screen-grid FET**
- Gate length and source-drain distance un-coupled leading to an alternative control of short channel effects:
- Second gating row acts as **DIBL control** and **reduces S**
- SGFET shows promising **low power AC** characteristics compared to a FDSOI MOSFET
- *Next stage:*
  - Digital characteristics: gate delay vs power information
  - Fabrication via e-beam and photo-lithography (INNOS, UK)